Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/777,677	STONE ET AL.	
Examiner	Art Unit	
Nguyen T. Ha	2831	

	SEAR	CHED	
Class	Subclass	Date	Examiner
361	366	21405	NY
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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